## Notice of References Cited Application/Control No. 10/620,543 Examiner David W. Scheuermann Applicant(s)/Patent Under Reexamination TAKAHASHI ET AL. Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,243,245	09-1993	Oba, Hiroshi	310/89
	В	US-4,893,043	01-1990	Baines, Roger F.	310/239
	O	US-4,853,576	08-1989	Mayumi et al.	310/239
	D	US-			
	Е	US-			
	F	US-			
	G	US-			
	Н	US-	-		
	ı	US-			
	J	US-			
	к	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	JP 53072108 A	06-1978	Japan	NOTO et al.	H02K 23/04
	0	·				
	Ρ					-
	α	•				
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

		<u>-</u>
*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	٧	
	w	
	х	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.